

# Spin-dependent Trap-assisted Tunneling in Ferromagnet-Oxide-Semiconductor Structures

Viktor Sverdlov and Siegfried Selberherr

*Institute for Microelectronics, TU Wien, Gußhausstraße 27-29, 1040 Vienna, Austria*  
e-mail: {Sverdlov|Selberherr}@iue.tuwien.ac.at

Silicon is an ideal material for spintronic applications due to its weak spin-orbit interaction and long spin lifetime [1,2]. Spin injection from a ferromagnetic electrode into n-type silicon was claimed at room [3] and elevated [4] temperatures. However, the amplitude of the spin-accumulation signal extracted from a three-terminal injection method [2,3] is orders of magnitude higher than predicted [1]. The reasons for this discrepancy are currently heavily debated [1,5-8]. Recently an alternative interpretation of the three-terminal signal based on spin-dependent magnetoresistance due to trap-assisted resonant tunneling was proposed [5]. However, the effects due to finite spin lifetime [6] were not taken into consideration. Here we investigate in detail the role of spin relaxation and decoherence on a trap in determining the trap-assisted tunneling magnetoresistance.

To elucidate the role of spin relaxation and decoherence we introduce the corresponding relaxation terms into a Lindblad equation for the density matrix evolution of spin on a trap. This results in coupled master equations for the density matrix elements in the presence of the spin lifetime  $T_1$  and decoherence time  $T_2$  ( $T_2 \leq T_1$ ) and the tunneling rates  $\Gamma_N$  from silicon and  $\Gamma_{\pm} = \Gamma_F(1-p)$  to the ferromagnet (Fig.1). The current  $I$  due to tunneling via a trap is different from  $I_0 = \Gamma_F \Gamma_N / (\Gamma_F + \Gamma_N)$  and depends on the angle  $\Theta$  between the spin quantization axis and the magnetization orientation.

$$I = e \frac{\Gamma_F(\Theta) \Gamma_N}{\Gamma_F(\Theta) + \Gamma_N},$$

$$\Gamma_F(\Theta) = \Gamma_F \left( 1 - p^2 \Gamma_F T_1 \left\{ \frac{\cos^2 \Theta}{\Gamma_F T_1 + 1} + \frac{T_2 \sin^2 \Theta (\Gamma_F T_2 + 1)}{T_1 \omega_L^2 T_2^2 + (\Gamma_F T_2 + 1)^2} \right\} \right). \quad (1)$$

$\omega_L$  is the Larmor frequency and  $p$  is the ferromagnetic interface current polarization. In the case  $T_1 = T_2 \rightarrow \infty$  the corresponding expression in [5] is recovered. In complement to [5], when  $\Gamma_F T_1 = \Gamma_F T_2 \ll 1$ , the resistance dependence on the magnetic field is of a Lorentzian shape with the half-width determined by the inverse spin lifetime. A short spin relaxation time suppresses the “spin blockade” [5] at small  $\Theta$  (Fig.2) in a similar fashion as the reduction of spin polarization  $p$  (Fig.3). Counterintuitively, due to a suppression of the last term in (1) at fixed  $T_1$ , the amplitude of the  $I(\Theta)$  modulation becomes larger for shorter  $T_2$  (Fig.4). In contrast to [5], at finite  $T_1$  the modulation of  $I(\Theta)$  is present at any trap position relative to the contacts (Fig.5). Finally, an unusual non-monotonic dependence with  $T_2$  of the magnetoresistance half-width as a function of the perpendicular magnetic field  $\mathbf{B}$ , with the linewidth decreasing, at shorter  $T_2$  is shown in Fig.6.

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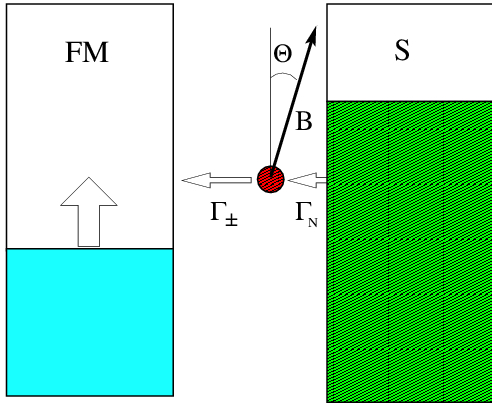


Fig.1: The trap is connected to electrodes with the rates  $\Gamma_N$  and  $\Gamma_{\pm}$ . A magnetic field  $\mathbf{B}$  defines the trap spin quantization axis  $OZ'$  at an angle  $\Theta$  to the magnetization orientation  $OZ$  in the ferromagnet.

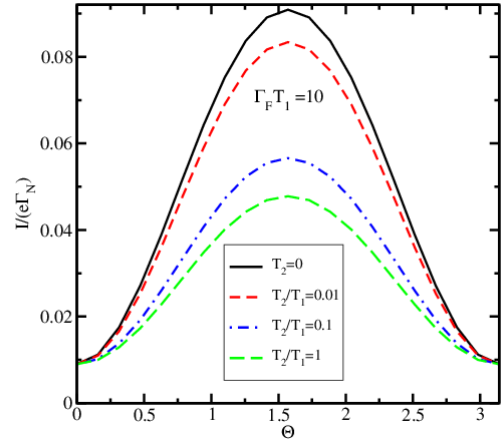


Fig.4: Current as a function of  $\Theta$ , for  $p=1$ ,  $\Gamma_N/\Gamma_F = 10$ ,  $\omega_L/\Gamma_F = 1$ ,  $\Gamma_F T_1 = 10$ , and several values of  $T_2/T_1$ .

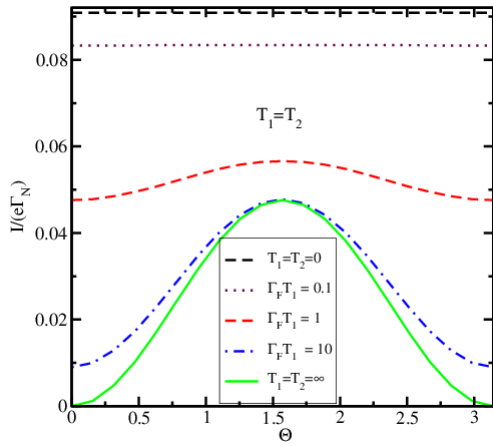


Fig.2: Current in units of  $e\Gamma_N$  as a function of  $\Theta$  for  $p=1$ ,  $\Gamma_N/\Gamma_F = 10$ ,  $\omega_L/\Gamma_F = 1$ , and several values of  $T_2=T_1$ .

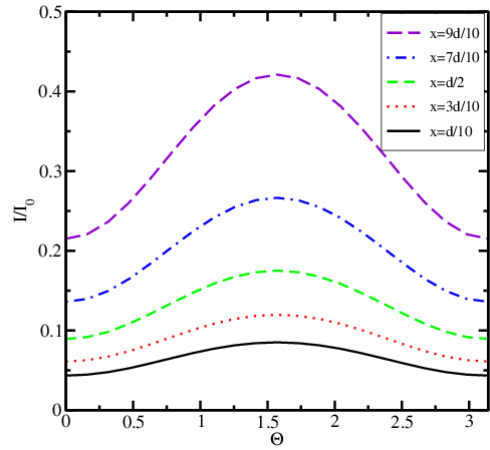


Fig.5 Normalized current as a function of the position  $x$  relative to silicon, for  $p=1$ ,  $\Gamma_N=\Gamma_0 \exp(-x/d)$ ,  $\Gamma_F=\Gamma_0 \exp(-(d-x)/d)$ ,  $T_2=T_1$ ,  $\omega_L T_2 = \Gamma_0 T_2 = 10$ .

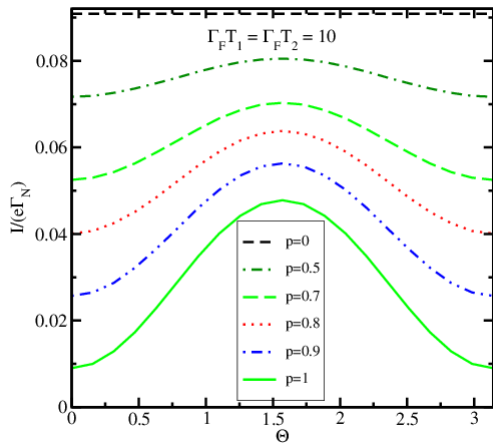


Fig.3: Current as a function of  $\Theta$ , for  $\Gamma_N/\Gamma_F = 10$ ,  $\omega_L/\Gamma_F = 1$ ,  $\Gamma_F T_1 = \Gamma_F T_2 = 10$ , and several values of  $p$ .

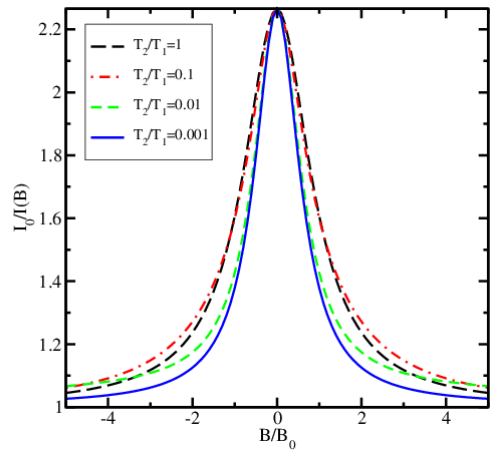


Fig.6: Magnetoresistance signal as a function of the perpendicular magnetic field  $\mathbf{B}$  for several  $T_2/T_1$ , for  $p=0.8$  and  $\Gamma_F T_1 = 10$ . The field  $\mathbf{B}_0$  is parallel to the magnetization in the ferromagnet.